

# CONTAINERLESS PROCESSING OF MOLTEN TIN SAMPLES IN A CONTROLLED OXYGEN ENVIRONMENT

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## [Abstract]

Contamination due to oxygen or oxide layer formation is a major concern in containerless processing of metallic melts. While experiments dealing with the studies of undercooling, nucleation, and observation of surface microstructures are influenced by even a surface monolayer, the problem is less acute for metals such as tin which have appreciable volatility for oxygen. The present study involves tin samples which were melted and resolidified inside a high temperature acoustic levitation chamber in a controlled low-oxygen environment. The processed samples were analyzed by sensitive surface analysis techniques (SEM/EDS and XPS) to determine oxygen distribution on the outside surface and the cross-section. Results indicate that contamination due to oxygen can be avoided provided outgassing from all heated surfaces is minimized.

## INTRODUCTION

Containerless experimentation with metallic melts requires a practically oxygen-free environment. Any significant residual levels of oxygen will result in a rapid metal oxide formation and alter the metallic transformations being studied. In experiments dealing with undercooling of metals, alloys and metallic glasses, entry of oxygen into the melt can initiate premature nucleation and forestall the supercooling process. In addition, surface properties, such as surface tension and emissivity are likely to change drastically due to the build up of any surface oxide. The surface oxide will also interfere with the observation of surface microstructure.

The oxygen sorbents developed under the Microgravity Advanced Development Activities program at JPL can, in theory, lower oxygen to parts-per-trillion (ppt) levels provided there is minimal outgassing from connecting lines and other surfaces in contact with the cleaned gas. If oxygen levels can be maintained at or below ppt levels, sufficient time is generally available for experimentation before even an oxide monolayer is formed. Even if oxygen levels could not be lowered to ppt levels (either because of outgassing or due to inadequate gas cleaning), there are metals (e.g. tin and copper) where even in the presence of a limited oxygen contamination, the metal oxide may not appear as a separate phase due to the solubility<sup>1</sup> of the oxide in the melt.

The objective of the present work is to establish that metallic melts can be processed in microgravity containerless experiments without contamination by an

external oxygen source, e.g. the sample environment. The experiments involved the processing of high purity samples of tin in a high temperature acoustic levitator. The tin samples were heated from room temperature to 300 °C, which is significantly above the melting point of tin of 232 °C. The processed samples were analyzed for the presence of the oxide (or oxygen) on the outer surface as well as in the cross-section. Such an analysis is crucial to determining whether processing of metallic melts can be carried out without incorporating unacceptable levels of oxygen contamination.

## EXPERIMENTAL

Two modes of gas purification were used. In the first mode, a commercial hydrox purifier (Matheson Gas Co.) was used and the gas in the processing chamber was recirculated in a closed loop and cleaned by its passage through the purifier. In the second mode, high purity argon was passed through a bed of copper zeolite (activated by reduction) before entering the high temperature acoustic levitator. The scrubbed argon gas provided the low-oxygen environment around the sample and then exited the levitator chamber through an exit port. The schematic for this mode of operation is shown in Figure 1. Details on the preparation of the activated oxygen sorbent bed and its oxygen uptake characteristics are given in References 2 and 3.

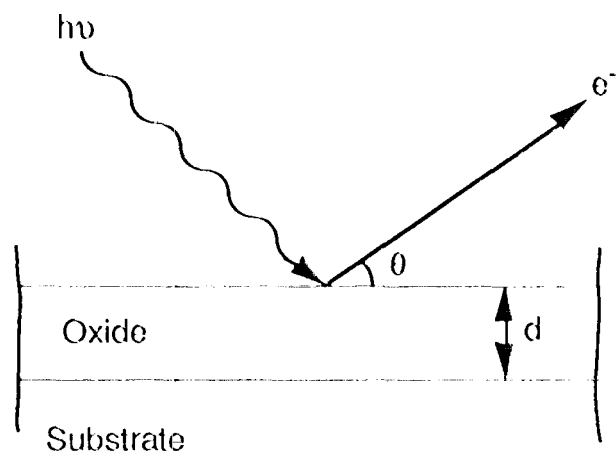
Tin metal samples were cut from a high purity (99.9999%) metal rod. They were transferred to the levitator by means of a teflon suction tube which lifted the sample pellet from a bottle and placed it on a zirconia plate through a port in the levitator chamber. After placing the metal sample on the zirconia plate inside the levitator chamber, the chamber port was capped off and the system was pumped down to  $10^{-7}$  torr. The chamber was then back filled with high purity argon at about 1 atm. Heating of the sample was then initiated by means of nichrome heaters inside the chamber. The argon purity inside the chamber was maintained by operation in one of the two modes described above. The total pressure inside the levitator was limited to just below 5 psig. The sample temperature was taken to be the same as that of the zirconia plate and was measured with a thermocouple. When the sample temperature reached the target value of 300 °C, it was maintained at this value for 30 minutes. Hereafter, sample heating was terminated and the system was allowed to cool down. When the sample temperature was close to room temperature (below 50 °C) and the gas purification systems properly cooled down, the sample was removed and placed in a secure glass bottle for subsequent analysis.

The analysis of the processed metal samples was carried out using Scanning Electron Microscopy with Energy Dispersive Spectrum (SEM/EDS) and by X-ray Photoelectron Spectroscopy (XPS). The outer surface of all processed samples and a few "as received" samples was analyzed. In addition, the processed tin samples were cut to expose the cross section for similar surface analysis.

## RESULTS AND DISCUSSION

Surface analysis on four different samples of "as received" (e.g. not contaminated by handling) tin was conducted by SEM/FDS and XPS. These samples were labeled Sn-3, Sri-6, Sri-7, and Sri-8.

Figure 2 shows the SEM/FDS scan obtained from the fresh sample Sri-3. This scan shows a main peak and some secondary peaks for Sn while only a very small peak for oxygen resulting from the surface oxide. In the XPS analysis on this sample, tin and oxygen peaks were clearly seen in the spectrum. Figure 3 shows the wide XPS scan for sample Sri-3 with tin and oxygen peaks while Figure 4 shows the Sn 3d peaks on an expanded scale of the binding energy for the same sample. Note in Figure 4 that the position of the taller peaks is for tin present as an oxide whereas the relatively smaller shoulder on the right is for tin present as a metal. The relative peak height of the taller peak (tin oxide) to the right shoulder peak (tin metal) leads to a rough estimate of the thickness of the oxide layer.



For an X-ray photon incident on a metal substrate with an oxide layer (see above diagram), the relative photoemission signal intensities (detected at angle  $\theta$ ) from the oxide and the metal may be expressed as:

$$\frac{I_{ox}}{I_{sub}} = \frac{D_{ox} \lambda_{ox}}{D_{sub} \lambda_{sub}} \frac{1 - \exp(-d/\lambda_{ox} \sin \theta)}{\exp(-d/\lambda_{ox} \sin \theta)} \quad (1)$$

where  $I$  is the signal intensity,  $D$  is the atomic number density,  $\lambda$  is the attenuation length of the photoelectrons,  $d$  is the oxide layer thickness, and the subscripts 'ox' and 'sub' refer to the oxide and the substrate, respectively. The relationship may be simplified by noting that the factor

$$D_{ox} \lambda_{ox} / D_{sub} \lambda_{sub}$$

is newly unity, and in the present measurements  
 $\theta = 350$  and  $\lambda = 20 \text{ \AA}$ .

By substituting these values in Equation (1), a simplified relationship is obtained between the ratio of the oxide and the substrate signal intensities and the oxide layer thickness  $d$ .

1 bus, estimates of the oxide layer thickness of the "as received" samples from XPS analyses were obtained and are shown in Table 1.

Table 1. Estimates of the oxide layer thickness for "as received" tin samples as obtained from XPS analysis.

SAMPLE ID	OXIDE LAYER THICKNESS, $\text{\AA}$
Sn-3	29
Sri-6	23
Sri-7	30
Sri-8	26

The results in Table I indicate that the average oxide layer thickness on the fresh tin samples was  $27 \text{ \AA}$ .

#### Samples Processed using the Hydrox Purifier

Samples Sri-1 and Sri-2 were processed using the hydrox purifier. At the end of melting and resolidifying, the samples were retrieved and analyzed by SEM/EDS and XPS.

Surface analysis of the samples by SEM/EDS is shown in Figures 5 and 6. It is seen that the oxygen peaks are more easily identifiable and are substantially larger than for the "as received" samples (cf. figure 2). XPS analysis obtained on the processed samples Sri-1 and Sri-2 are shown (on expanded binding energy scale) in Figures 7 and 8, respectively. These figures show that the shoulder (representing tin as metal) on the right side of the main peak (tin as oxide) is now much smaller for both samples, implying an increased oxide layer due to processing. The estimated oxide layer thicknesses are  $41 \text{ \AA}$  for Sri-1 and  $42 \text{ \AA}$  for Sri-2, as shown in Table II.

#### Samples Processed using Gas Scrubbed through the Zeolite Bed

The tin samples processed using purified argon gas obtained after scrubbing through the copper zeolite bed were labeled Sri-4 and Sri-5.

Surface analysis of the processed samples Sri-4 and Sri-5 by SEM/EDS is shown in Figures 9 and 10, respectively. It is seen from Figure 9 that practically no oxygen peak is detected whereas there is a small oxygen peak present in Figure 10. XPS analysis on samples Sri-4 and Sri-5 is shown in figures 11 and 12, respectively, which show the Sn 3d peaks on an expanded binding energy scale. It is seen from Figure 11 (sample Sri-4) that the right shoulder peak (corresponding to tin metal) is quite pronounced. However, from Figure 12 (sample Sri-5), the right shoulder peak is rather small. These results suggest that the oxide layer thickness is greater for sample Sri-5 than for sample Sri-4. Quantitative estimates of the oxide layer thickness may again be made using the ratio of the signal intensities corresponding to tin as oxide and tin as metal, respectively. The results obtained are 24 Å for Sri-4 and 37 Å for Sri-5 as shown in Table II. Due to the higher oxide layer thickness of sample Sri-5 compared to the average oxide layer thickness of fresh samples, it would appear that this sample picked up some contamination during processing. This probably resulted from inadequate outgassing of the levitator chamber parts during processing of this sample. Sample Sri-4, on the other hand, compares well with the fresh samples and shows no evidence of contamination.

Table II. Estimates of the oxide layer thickness for processed tin samples obtained from XPS analysis.

SAMPLE ID	SURFACE ANALYZED	OXIDE LAYER THICKNESS, Å
Sri-1	OUTER	41
Sri-2	OUTER	42
Sri-4	OUTER	24
Sri-5	OUTER	37
Sri-2	SECTION	24
Sri-4	SECTION	21

### Sample Cross-Section Analysis

Cross section analysis was conducted on samples Sri-2 (processed with gas recirculation using Hydrox purifier) and Sri-4 (processed with gas scrubbed through the zeolite bed).

The metal samples were cut at the middle into two pieces using a sharp cutting edge. The freshly exposed surface from the interior of each sample was analyzed by SEM/EDS and XPS.

Figures 13 and 14 show the SEM/EDS scans obtained for the cross-sectional surfaces of Sri-2 and Sri-4, respectively. Note that Figure 13 (sample Sri-2) shows only a very small signal peak for oxygen while Figure 14 (sample Sri-4) shows almost no oxygen. Figures 15 and 16 show the Sn 3d peaks in the XPS spectrum on an expanded binding energy scale. For both of these samples, it is

seen that the shoulder peaks corresponding to tin (as metal) are significant. More quantitatively, an oxide layer thickness of  $24\text{ \AA}$  is obtained for the cross-section of Sri-? and  $21\text{ \AA}$  for the cross-section of Sri-4.

The above results suggest that a lower amount of oxygen is present on the cross section than on the surface for both samples, and the cross-section of Sri-4 has lower oxygen than the cross-section of Sri-?. These results are in agreement with the outer surface analyses for samples Sri-? and Sri-4 which indicate that the outer surface of sample Sri-4 gained no additional oxygen during the melt processing while sample Sri-2 had picked up some oxygen contamination.

Future work will involve melting and resolidifying metal samples inside an environmental control chamber at JPL. The gas inside the chamber will be cleaned using the JPL-developed sorbents for removing oxygen and water vapor. The metal samples will be melted using beam heating and other heating techniques being currently evaluated.

## CONCLUSIONS

These results indicate that tin samples can be processed (by subjecting them to the melting and resolidifying cycle) inside a positioner chamber in a sufficiently pure gas environment provided by scrubbing through a bed of copper zeolite. Such processing will not add oxygen to the sample beyond what is already deposited on the fresh sample. The results also indicate that if the heated components are not properly outgassed, oxygen contamination will result.

## ACKNOWLEDGMENTS

The research described in this paper was carried out at the Jet Propulsion Laboratory, California Institute of Technology, under a Contract with the National Aeronautics and Space Administration (NASA). This work is part of a comprehensive strategy for contamination control/management in NASA's Modular Containerless Processing Facility (MCPF) being developed for the Space Station Freedom. The authors would like to thank Mr. John Gatewood for his assistance with the operation of the acoustic levitator, Dr. Richard Vasquez for the XPS analysis, and Mr. Ron Ruiz for the SEM analysis.

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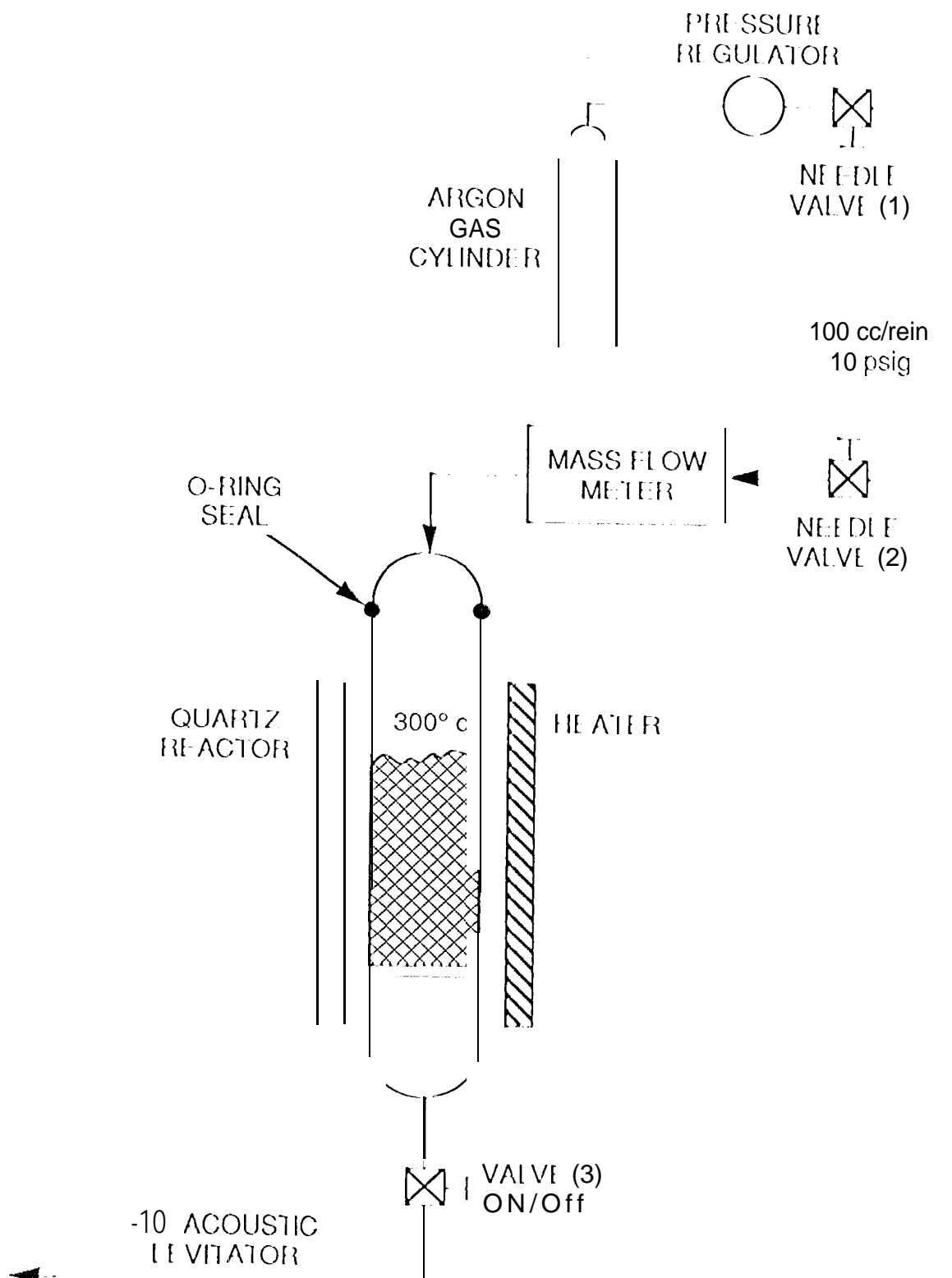


Figure 1. Schematic of Experimental Set Up for Supplying Oxygen-free Argon to the Acoustic levitator





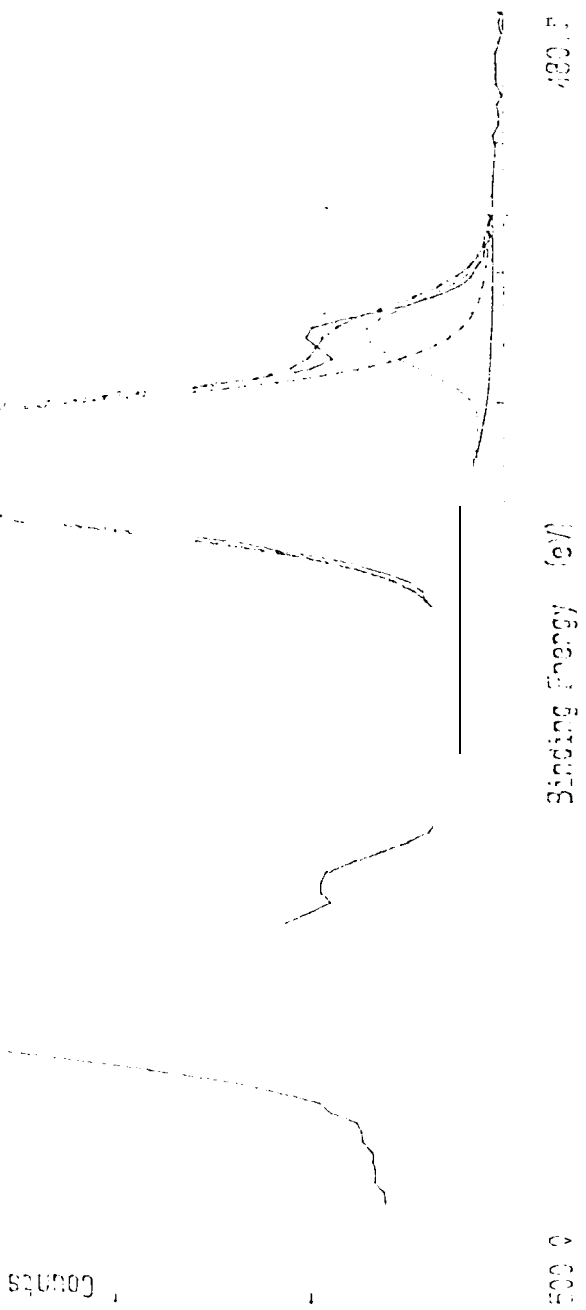


File: 2/2/1990 Date: 1/14/1990 Scan: 300 Flood Gun: 0.0 eV  
 Region 2 Disc: 20916 # of Scans: 10 F050 Vol: 0% 2  
 Pos: 10510° Sn-3 0002000: 00

27155  
 Energy Width ea % 20 2 25 Sub: 502 eV

185.86 1.70 52398 97.8 0.00  
 184.93 1.15 14515 8.2 2.02

80% Gaussian  
 Last chi-square: 5.252



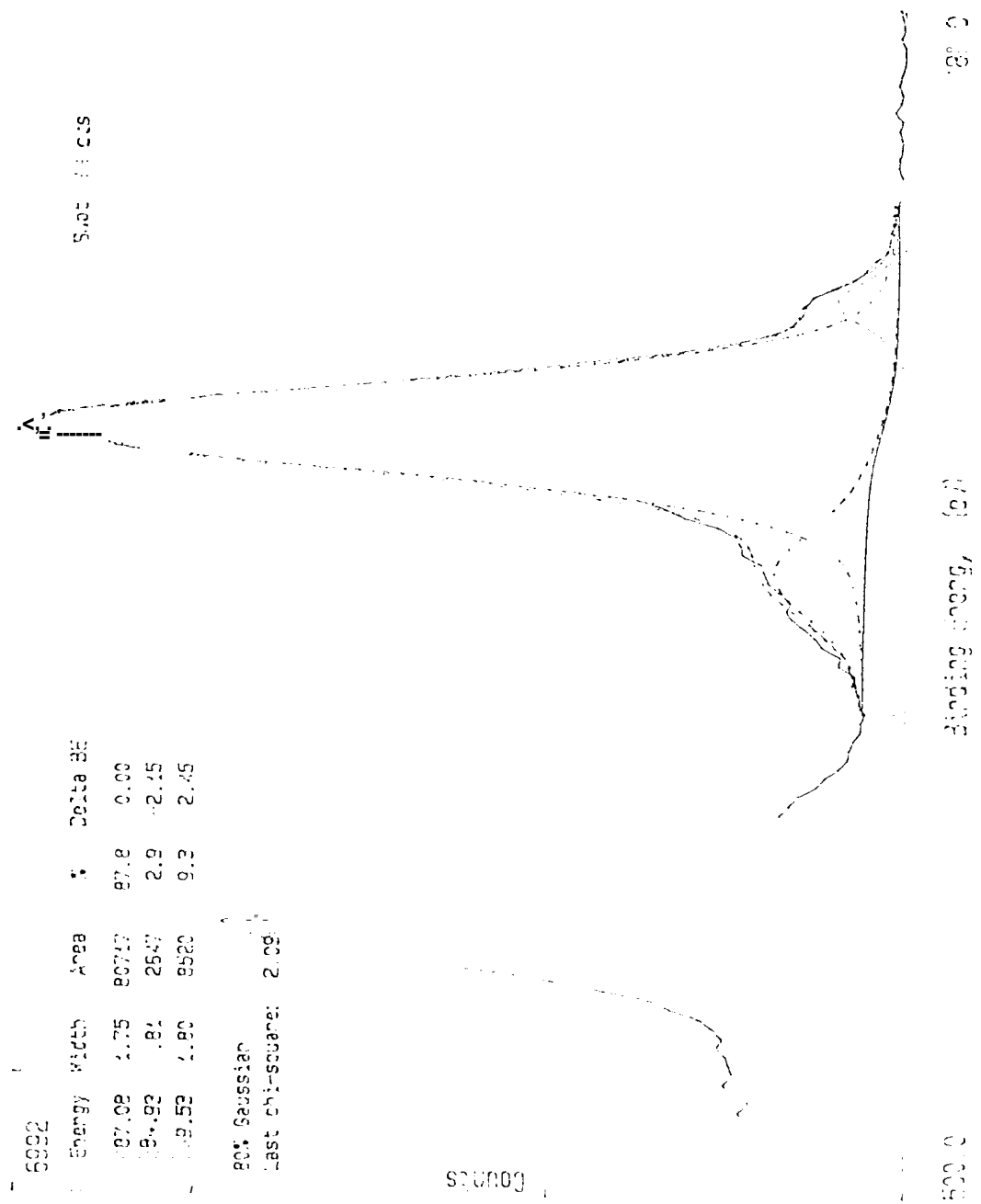
Report #: Sn 30

Figure 12.4 XPS Scan of Sn 3d Peaks for Sample Sn-3 Surface





File: 071119V 2 Date: 1999 Scan: 300 0 Flood Gun: 0.0 eV  
 Region 2 0 SCI 40925 4 of Scans: 0 Resolution: 2  
 Description: Sn 3d Coregion: 44



Region 1: Sn 3d

Figure 10.7. XPS Scan of Sn 3d Peaks for Sample Sn-1 Surface

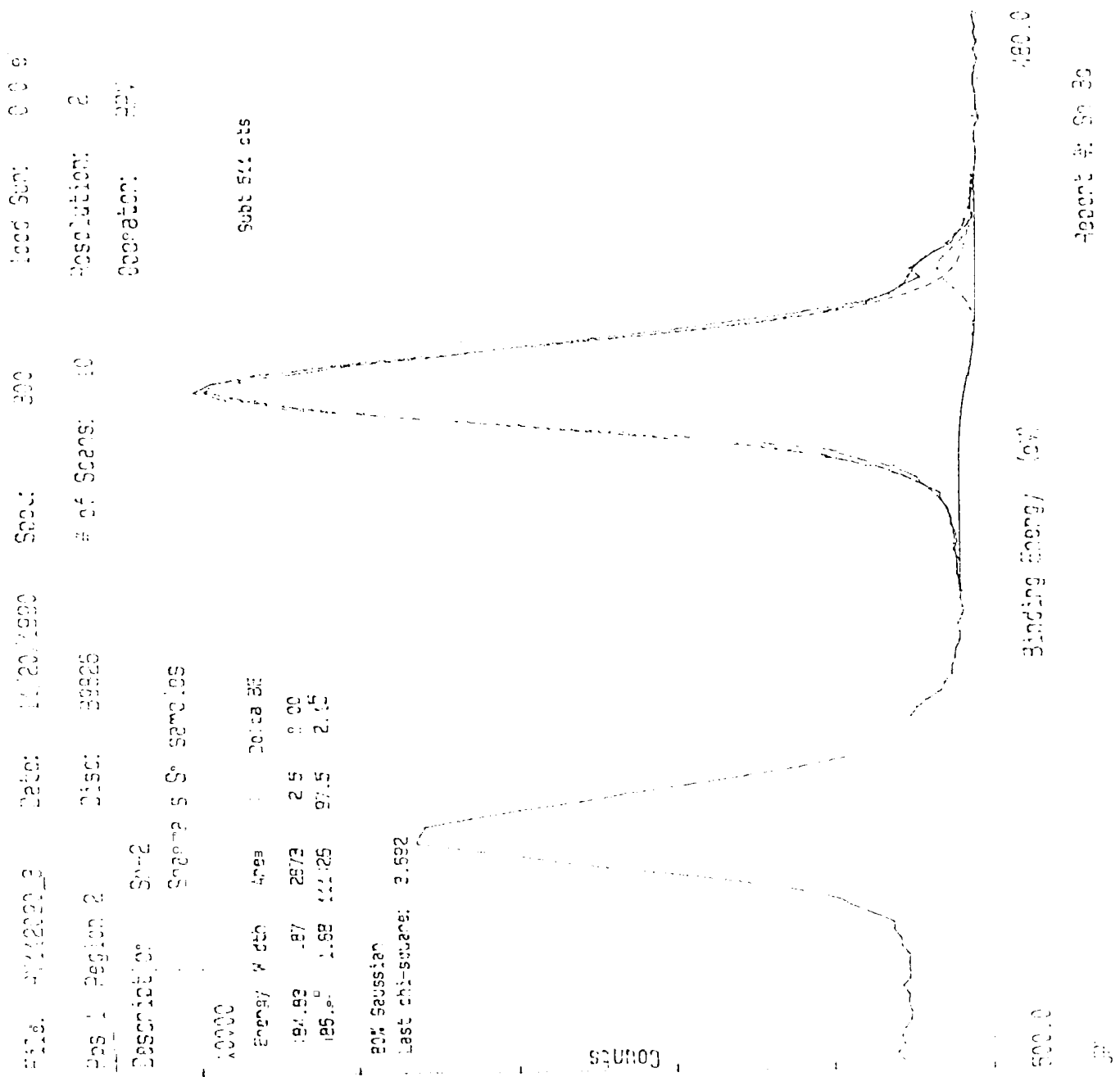


Figure 2.8 XPS Scan of Sn 3d Peaks for Sample Sn-2 Surface

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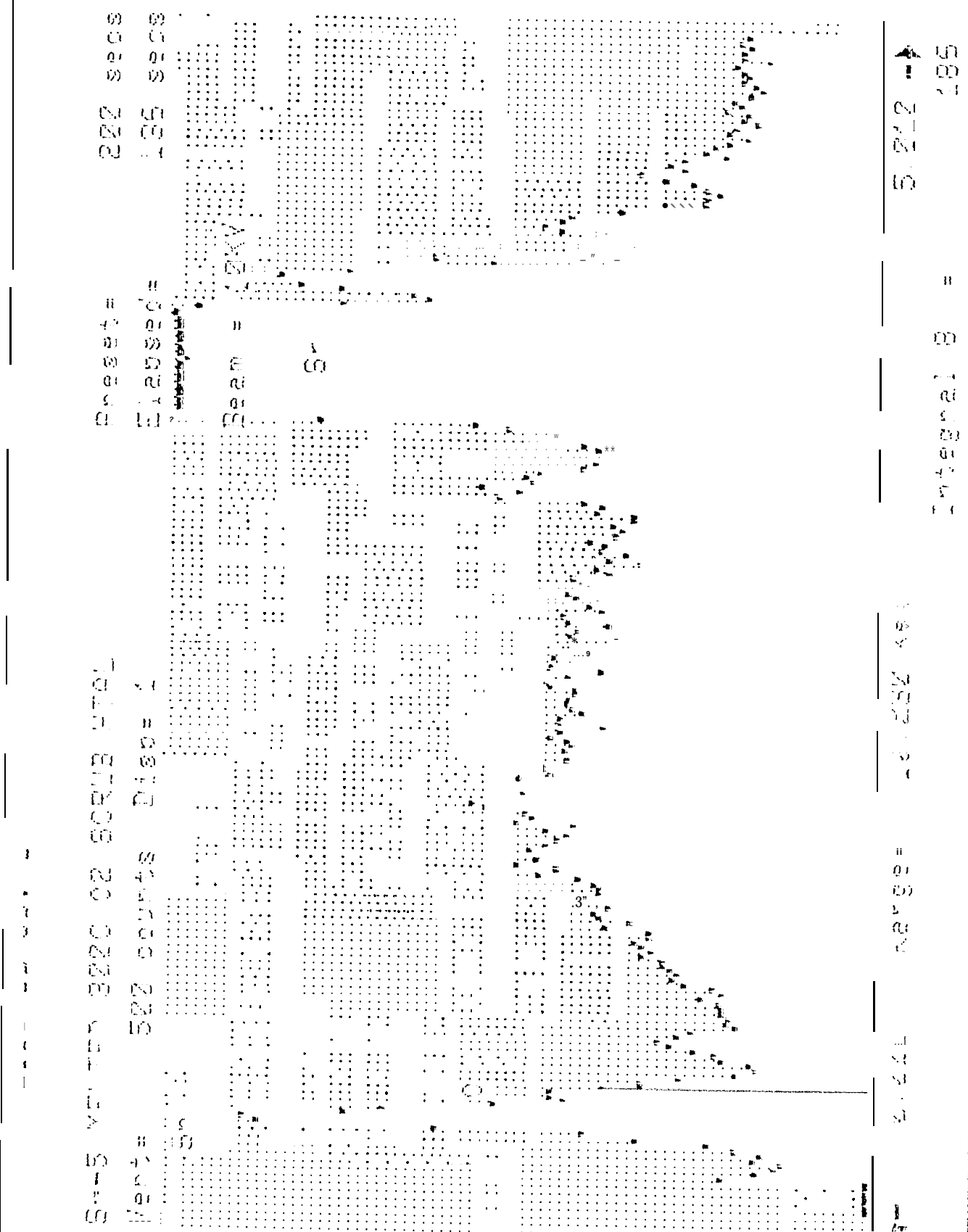


Figure 28/10 SEM/EDS Scan for Sample Sn-5 Surface

File: 201 490.2 Date: 1/17/2000 Scan: 300 1000 Scan: 0.0 eV  
 Region: 2 Disc: 49926 No. of Scans: 10 Resolution: 2 Degradation: 0.07

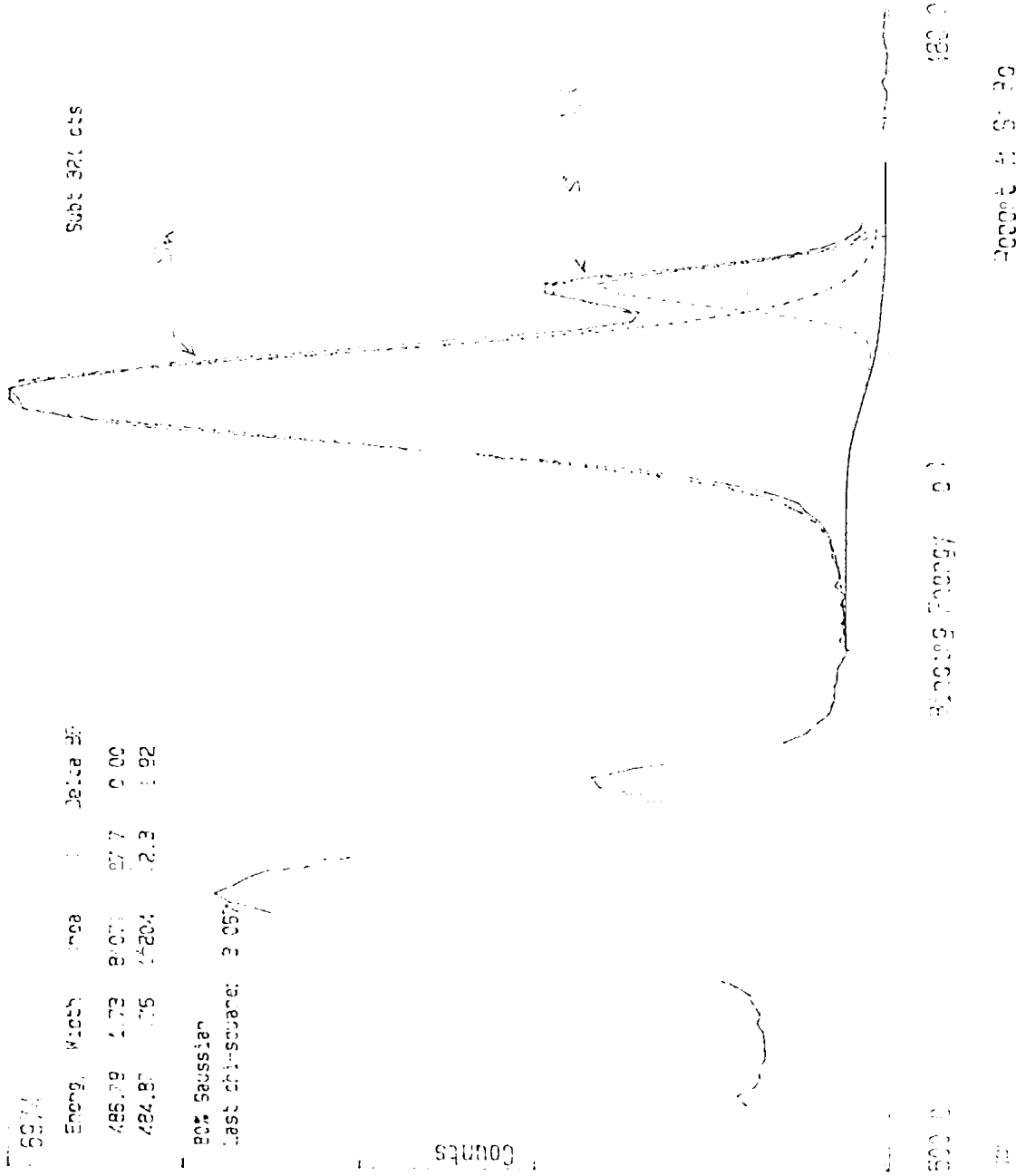


Figure 2511 XPS Scan of Sn 3d Peaks for Sample Sn-4 Surface

File: 07/12/2000\_2 Date: 11/20/1990 Scan: 300 Sub: 459 cts  
 Pos 2 Region 2 Disc: 30825 # of Scans: 10 Resolution: 1  
 Description: Sn 5 Charge: 22

Sample: Sn 5270 05

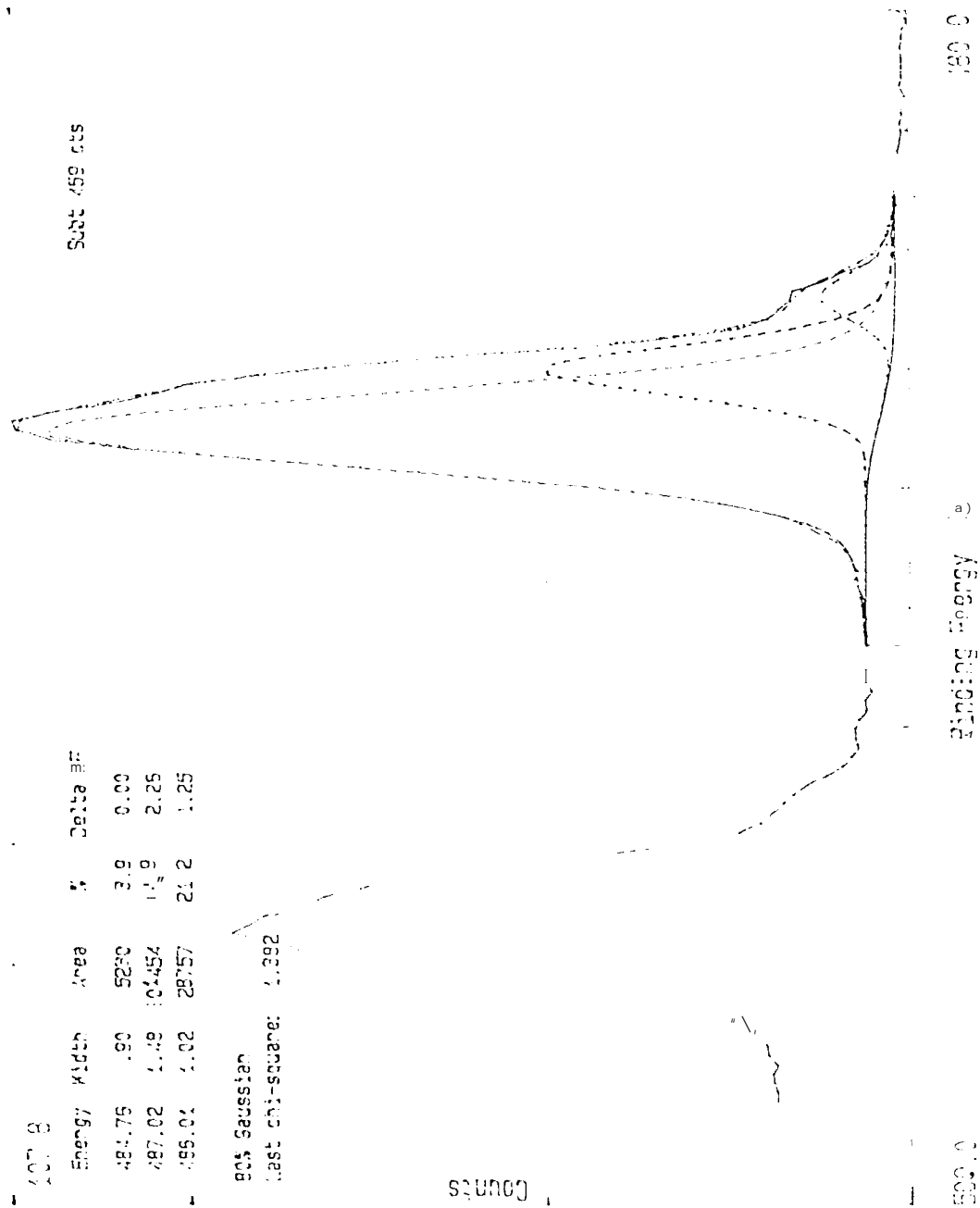
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Energy	Width	Area	N	Delta EF
484.76	.90	5230	3.9	0.00
487.02	1.48	10454	11.9	2.26
489.01	1.02	28757	21.2	1.25

80% Gaussian

Last chi-square: 1.292

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Figure 27/12 XPS Scan of Sn 3d Peaks for Sample Sn-5 Surface

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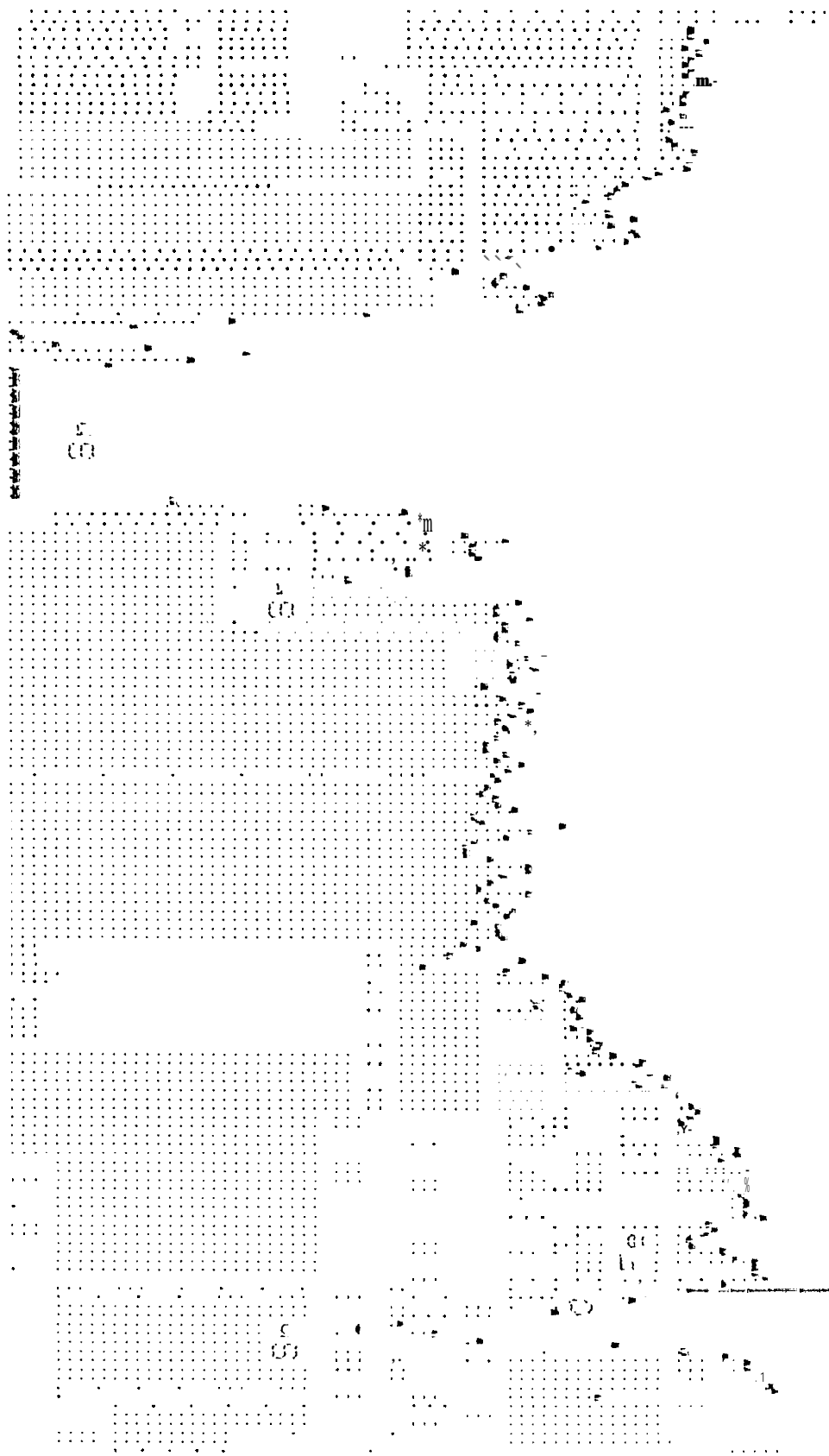
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Figure 28/3 SEM/EDS Scan for Sample Sn-2 Cross Section

12-080-0002 14:21:00

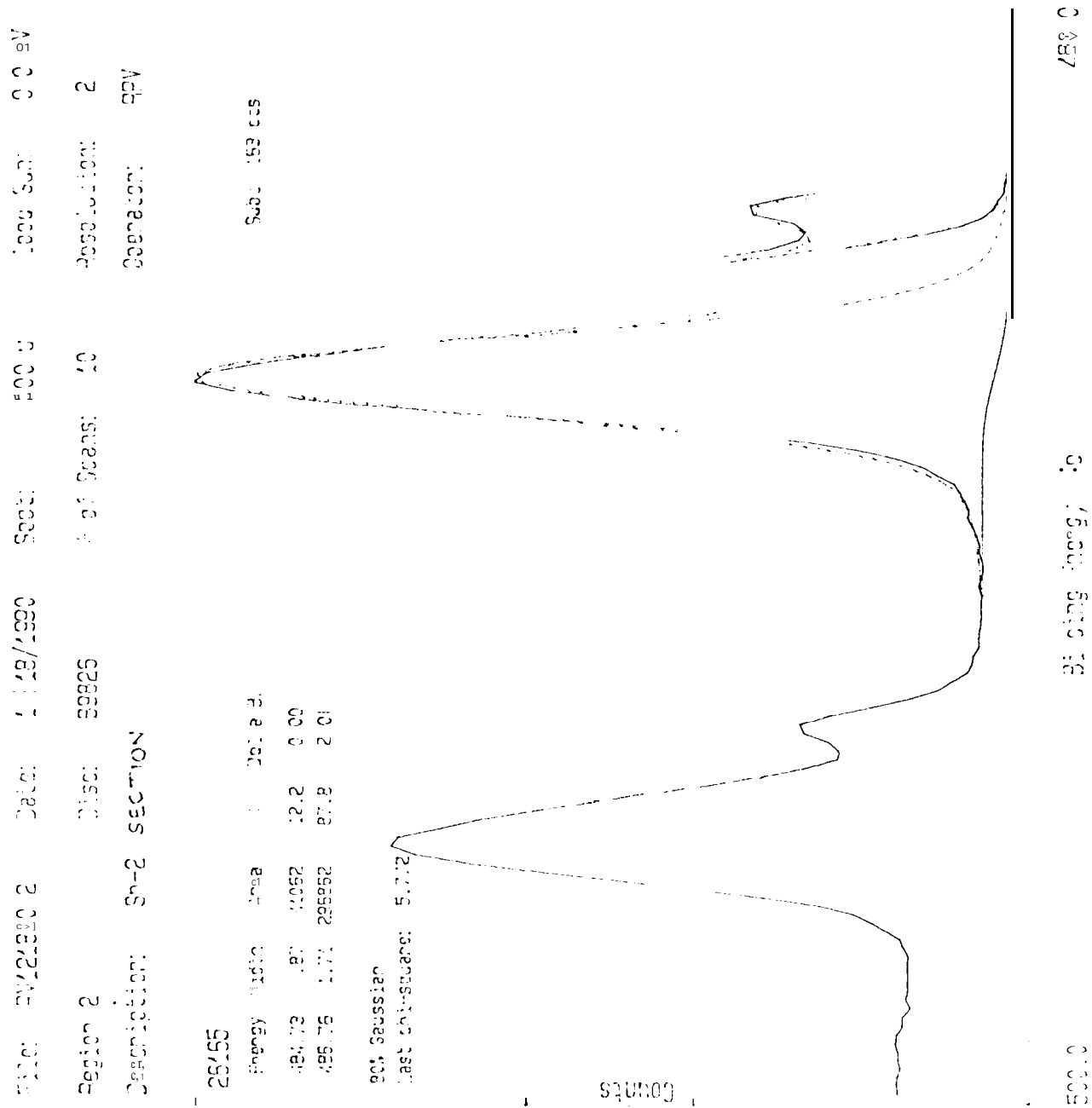
Sn-4-SEI-0000 ED 3220 02 5000 1000  
Y-axis = 500 counts X-axis = 1000  
Z-axis = 1000



4-0-000 Range = 10.000 10.000 10.000  
Integral 0 = 0.000

Figure 2014 SEM/EDS Scan for Sample Sn-4 Cross Section

Figure 3d XPS for Sn 3d



File: PV21990.1 Date: 12/18/1990 Scan: 5000 Flood Scan: 0.0 eV  
 Region 2 Disc: 88925 1.01 Scans: 10 Resolution: 2 Acq: 88V  
 Description: Sn-4 SECTION

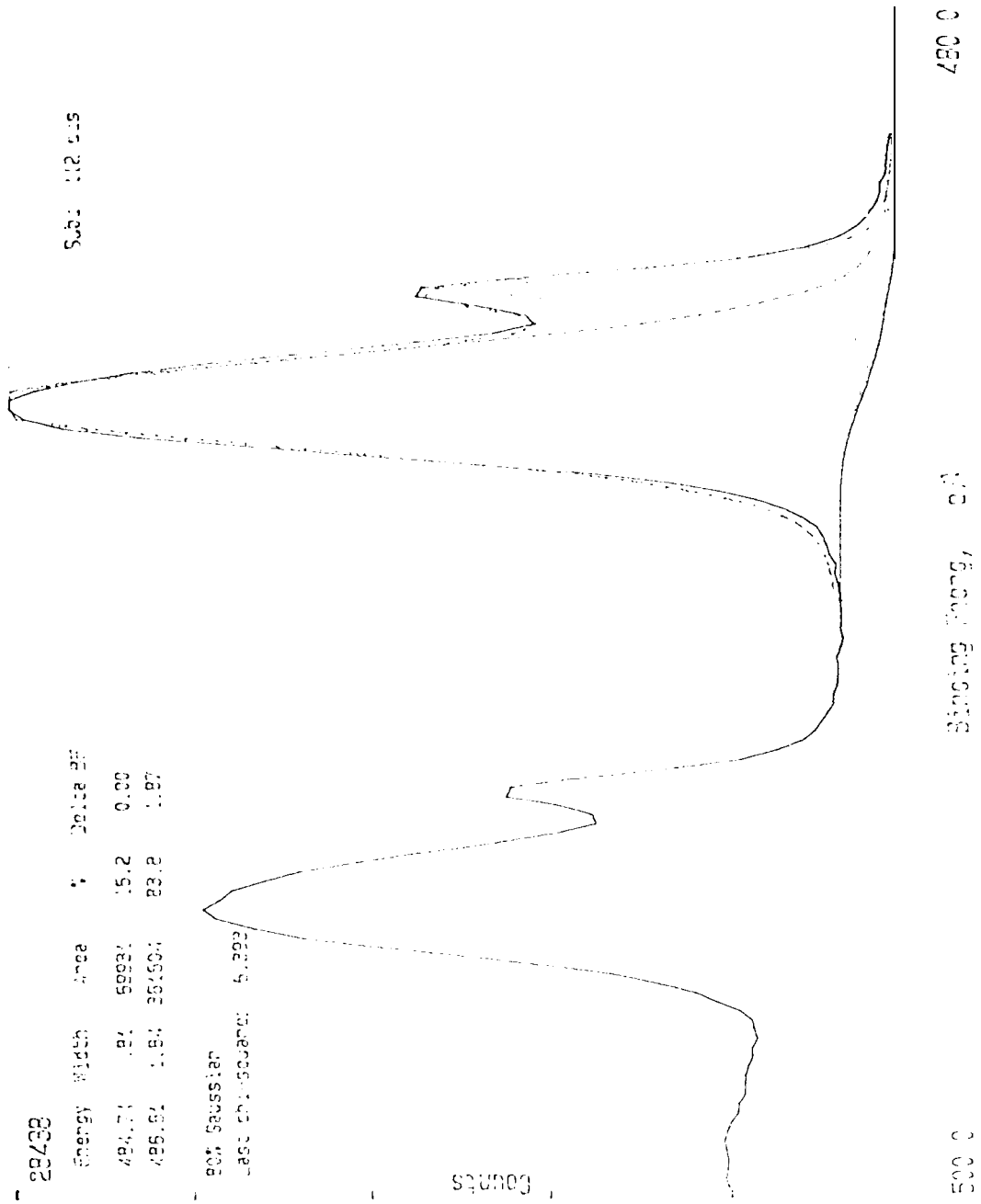


Figure 20 XPS Scan for Sn 3d Peaks for Sample Sn-4 Cross Section